

FRAUNHOFER CENTER FOR SILICON PHOTOVOLTAICS CSP



- 1 High resolution ICPMS.
- 2 Silicon samples.

LOCALIZATION OF INORGANIC IMPURITIES IN SILICON SAMPLES

Fraunhofer Center for Silicon Photovoltaics CSP

Otto-Eissfeldt-Strasse 12 06120 Halle (Saale) | Germany

Contact

Dr. Sylke Meyer Telephone +49 345 5589 5116 sylke.meyer@csp.fraunhofer.de

www.csp.fraunhofer.de

Surface, Sub-surface and Bulk

- Processing steps like cracking, grinding, sawing and milling cause severe contaminations at the surface which may diffuse into the bulk.
- Localized trace element analysis can answer the following questions:
 - Where are impurities localized in the material?
 - ➡ How can the material be purified?
 - Sequential etching and subsequent ICPMS analysis is a useful tool for layer dependent trace element analysis

Our Services

- Analytical service for silicon chunks, granules, powder, wafer etc.
- Quantitative determination of trace elements on the surface, within oxide and sub-oxide layers or bulk
- Customized method development
- Contamination evaluation of new process steps
- Specification of product quality



Advantages

Further Information

- Reliable and precise method for sequential etching
- High sensitivity
- Suitable for different degrees of purities / types of sample
- Adaptable to various kinds of samples according to question
- Useful tool to locate impurities and evaluate cleaning strategies
- Wahl, S.; Meyer, S.; Hagendorf, C.: Localization of Inorganic Impurities in Silicon Samples by Sequential Etching and ICP-MS Detection, 6th International Conference on Silicon Photovoltaics, SiliconPV 2016
- Wahl, S.; Meyer, S.; Hagendorf, C.: Advanced Metal Contamination Analysis for High Efficiency Solar Cell Manufacturing, 6th International Conference on Silicon Photovoltaics, SiliconPV 2016



Granulate



Chunks



Wafers



Powder

- 1 ICPMS results: silicon chunk.
- 2 Determination of surface area by 3D scanning



3 Sequential etching and subsequent ICPMS analysis for layer dependent trace element analysis.